

## CLAIMS

What is claimed is:

1. An integrated circuit structure, comprising:  
NMOS and PMOS transistors, at least some of said PMOS transistors being formed in N-well diffusions in a semiconductor material; and  
5 a blanket P-type diffusion component having a peak concentration depth more than twice that of said p-well.
2. An integrated circuit structure, comprising:  
a first population of a first dopant in a semiconductor, said first population occupying a first region of said semiconductor;  
a second population of said first dopant occupying a second region  
5 of said semiconductor, said second region being at a deeper implant depth than said first region;  
a second dopant occupying said second region of said semiconductor;  
wherein said second dopant is of opposite electrical ionization than  
10 said first dopant.

3. A fabrication method, comprising the steps of:

a) implanting first dopant atoms into a semiconductor body to create a first-conductivity-type well diffusion therein; and

5        b) implanting second dopant atoms into said semiconductor body, with more than twice the stopping distance and less than one-quarter of the dosage per unit area as said step a), to compensate atoms which channeled during said step a).

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